

Technical documentation





SN74LV164A-Q1 SCLS886 – DECEMBER 2022

SN74LV164A-Q1 Automotive 8-Bit Parallel-Out Serial Shift Registers

1 Features

Texas

INSTRUMENTS

- AEC-Q100 qualified for automotive applications:
 - Device temperature grade 1: –40°C to +125°C, T_A
 - Device HBM ESD Classification Level 2
 - Device CDM ESD Classification Level C6
- 2-V to 5.5-V V_{CC} operation
- Maximum t_{pd} of 10.5 ns at 5 V
- Typical V_{OLP} (output ground bounce) < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (output V_{OH} undershoot)
 > 2.3 V at V_{CC} = 3.3 V, T_A = 25°C
- loff supports live insertion, partial power-down mode, and back-drive protection
- Support mixed-mode voltage operation on all ports
- Latch-up performance exceeds 250 mA per JESD 17

2 Applications

- Output expansion
- LED matrix control
- 7-segment display control

3 Description

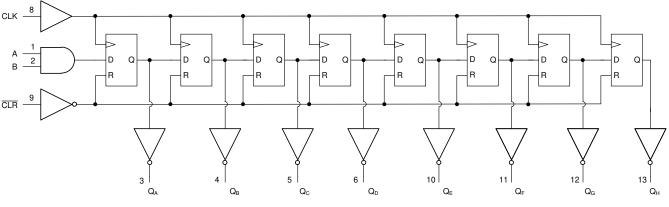
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The SN74LV164A-Q1 devices are 8-bit parallel-out serial shift registers designed for 2-V to 5.5-V $\rm V_{CC}$ operation.

Device	Information ⁽	1)
	mornation	

PART NUMBER PACKAGE		BODY SIZE (NOM)		
SN74LV164A-Q1	BQA (WQFN, 14)	3.00 mm × 2.50 mm		

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Logic Diagram (Positive Logic)



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4 Revision History

DATE	REVISION	NOTES
December 2022	*	Initial Release



5 Pin Configuration and Functions

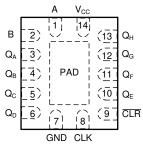


Figure 5-1. BQA Package, 14-PIN WQFN (Top View)

Table 5-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.		DESCRIPTION
A	1	ļ	Serial input A
В	2	ļ	Serial input B
Q _A	3	0	Output A
Q _B	4	0	Output B
Q _C	5	0	Output C
Q _D	6	0	Output D
GND	7	G	Ground pin
CLK	8	I	Storage clock
CLR	9	I	Storage clear
Q _E	10	0	Output E
Q _F	11	0	Output F
Q _G	12	0	Output G
Q _H	13	0	Output H
Q _{H'}	11	0	Q _H inverted
V _{CC}	14	Р	Power pin
Thermal pad		_	Thermal pad ⁽²⁾

(1) I = Input, O = Output, I/O = Input or Output, G = Ground, P = Power.

(2) WBQA package only



6 Specifications 6.1 Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		-0.5	7	V
VI	Input voltage ⁽²⁾		-0.5	7	V
Vo	Voltage applied to any output in the high-impedance or power-off state ⁽²⁾		-0.5	7	V
Vo	Output voltage ^{(2) (3)}		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V ₁ < 0		-20	mA
I _{OK}	Output clamp current	V ₀ < 0		-50	mA
I _O	Continuous output current	$V_0 = 0$ to V_{CC}		±25	mA
	Continuous current through V_{CC} or GND			±50	mA
T _{stg}	Storage temperature		-65	150	°C

(1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

(3) This value is limited to 5.5 V maximum.

6.2 ESD Ratings

			VALUE	UNIT
	Electrostatic	Human body model (HBM), per AEC Q100-002 HBM ESD Classification Level $2^{(1)}$	±4000	
V _(ESD)	discharge	Charged device model (CDM), per AEC Q100-011 CDM ESD Classification Level C4B	±2000	V

(1) AEC Q100-002 indicate that HBM stressing shall be in accordrance with the ANSI/ESDA/JEDEC JS-001 specification.



6.3 Recommended Operating Conditions

over recommended operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage		2	5.5	V
		V _{CC} = 2 V	1.5		
V	Llich lovel input veltage	V_{CC} = 2.3 V to 2.7 V	V _{CC} × 0.7		V
V _{IH}	High-level input voltage	V _{CC} = 3 V to 3.6 V	V _{CC} × 0.7		v
		V_{CC} = 4.5 V to 5.5 V	V _{CC} × 0.7		
		V _{CC} = 2 V		0.5	
V _{IL}	Low-level input voltage	V_{CC} = 2.3 V to 2.7 V		V _{CC} × 0.3	V
	Low-level input voltage	V _{CC} = 3 V to 3.6 V		$V_{CC} \times 0.3$	v
		V_{CC} = 4.5 V to 5.5 V		$V_{CC} \times 0.3$	
VI	Input voltage	·	0	5.5	V
Vo	Output voltage		0	V _{CC}	V
		V _{CC} = 2 V		-50	μA
		V_{CC} = 2.3 V to 2.7 V		-2	
I _{ОН}	High-level output current	V _{CC} = 3 V to 3.6 V		-6	mA
		V_{CC} = 4.5 V to 5.5 V		-12	
		V _{CC} = 2 V		50	μA
I	Low-level output current	V_{CC} = 2.3 V to 2.7 V		2	
I _{OL}		V _{CC} = 3 V to 3.6 V		6	mA
		V_{CC} = 4.5 V to 5.5 V		12	
		V _{CC} = 2.3 V to 2.7 V		200	
Δt/Δv	Input transition rise or fall rate	V _{CC} = 3 V to 3.6 V		100	ns/V
		V_{CC} = 4.5 V to 5.5 V		20	
T _A	Operating free-air temperature		-40	125	°C

(1) All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*.

6.4 Thermal Information

		SN74LV164A-Q1	
	THERMAL METRIC ⁽¹⁾	BQA (WQFN)	UNIT
		14 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	88.3	
R _{θJC(top)}	Junction-to-case (top) thermal resistance	90.9	
R _{θJB}	Junction-to-board thermal resistance	56.8	*011/
Ψ _{JT}	Junction-to-top characterization parameter	9.9	- °C/W
Ψ _{JB}	Junction-to-board characterization parameter	56.7	
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	33.4	

(1) For more information about traditional and new thermal metrics, see IC Package Thermal Metrics

6.5 Electrical Characteristics

DADAMETED	TEST CONDITIONS		-40°C	C to 125°C			
PARAMETER	TEST CONDITIONS	V _{cc}	MIN	ТҮР	MAX	UNIT	
	I _{OH} = -50 μA	2 V to 5.5 V	V _{CC} – 0.1				
V _{OH}	I _{OH} = -2 mA	2.3 V	2			V	
	I _{OH} = -6 mA	3 V	2.48				
	I _{OH} = -12 mA	4.5 V	3.8				
	I _{OL} = 50 μA	2 V to 5.5 V			0.1		
V _{OL}	I _{OL} = 2 mA	2.3 V			0.4	V	
	I _{OL} = 6 mA	3 V			0.44		
	I _{OL} = 12 mA	4.5 V			0.55		
l _l	V _I = 5.5 V or GND	0 to 5.5 V			±1	μA	
I _{CC}	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5			20	μA	
l _{off}	V_{I} or V_{O} = 0 to 5.5 V	0			5	μA	
Ci	V _I = V _{CC} or GND	3.3 V		2.2		pF	

over recommended operating free-air temperature range (unless otherwise noted)

6.6 Timing Requirements: V_{CC} = 2.5 V ± 0.2 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

			T _A = 25°	C	–40°C to 125°C		UNIT
		MIN	MAX	MIN	MAX	UNIT	
t _w Pulse duration	CLR low	6		6.5		20	
	Pulse duration	CLK high or low	6.5		7.5		ns
+	Setup time	Data before CLK↑	6.5		8.5		20
t _{su} Setup time	CLR inactive	3		3		ns	
t _h	Hold time	Data after CLK↑	-0.5		0		ns

6.7 Timing Requirements: V_{CC} = 3.3 V ± 0.3 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

			T _A = 25°	C	–40°C to 12	5°C	UNIT
			MIN	MAX	MIN	125°C MAX	UNIT
	Pulse duration	CLR low	5		5		ns
L _W		CLK high or low	5		5		115
	Setup time	Data before CLK↑	5		6		20
t _{su}	Setup time	CLR inactive	2.5		2.5		ns
t _h	Hold time	Data after CLK↑	0		0		ns



6.8 Timing Requirements: V_{CC} = 5 V ± 0.5 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

	1 9			/ \	/		
			T _A = 25°0	C	–40°C to 125°	°C	UNIT
			MIN	MAX	MIN	IIN MAX 5	UNIT
	Pulse duration	CLR low	5		5		20
'w		CLK high or low	5		5		ns
	Setup time	Data before CLK↑	4.5		4.5		20
^L SU	Setup time	CLR inactive	2.5		2.5		ns
t _h	Hold time	Data after CLK↑	1		1		ns

6.9 Switching Characteristics: V_{CC} = 2.5 V ± 0.2 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	LOAD	T,	_A = 25°C		-40°C to 12	5°C	UNIT
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
f			C _L = 15 pF	55	105		50		MHz
Imax			C _L = 50 pF	45	85		40		IVITIZ
t _{pd}	CLK	Q	0 = 15 = 5		9.2	17.6	1	21	
t _{PHL}	CLR	Q	C _L = 15 pF		8.6	16	1	18.5	ns
t _{pd}	CLK	Q	C = 50 pE		11.5	21.1	1	25	n 0
t _{PHL}	CLR	Q	C _L = 50 pF		10.8	19.5	1	22.5	ns

6.10 Switching Characteristics: V_{CC} = 3.3 V ± 0.3 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	LOAD	T,	_A = 25°C		-40°C to 12	5°C	UNIT
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
f			C _L = 15 pF	80	155		65		MHz
Imax			C _L = 50 pF	50	120		45		IVITIZ
t _{pd}	CLK	Q	0 - 15 - 15		6.4	12.8	1	16	
t _{PHL}	CLR	Q	C _L = 15 pF		6	12.8	1	16	ns
t _{pd}	CLK	Q	C = 50 pE		8.3	16.3	1	19.5	n 0
t _{PHL}	CLR	Q	C _L = 50 pF		7.9	16.3	1	19.5	ns

6.11 Switching Characteristics: $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	LOAD	T,	₄ = 25°C		-40°C to 12	25°C	UNIT
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
f			C _L = 15 pF	125	220		95		MHz
Imax			C _L = 50 pF	85	165		65		WITZ
t _{pd}	CLK	Q	C _L = 15 pF		4.5	9	1	11.5	20
t _{PHL}	CLR	Q	С <u></u> – 15 рг		4.2	8.6	1	11	ns
t _{pd}	CLK	Q	C _L = 50 pF		6	11	1	13	
t _{PHL}	CLR	Q	- С _L – 50 рг		5.8	10.6	1	13	ns

6.12 Noise Characteristics⁽¹⁾

 V_{CC} = 3.3 V, C_L = 50 pF, T_A = 25°C

	PARAMETER	SN74	LV164A-0	ຊ1	UNIT
	FARAMETER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.28	0.8	V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.22	-0.8	V





V_{CC} = 3.3 V, C_{L} = 50 pF, T_{A} = 25°C

	PARAMETER	SN74	LV164A-0	ג1	UNIT
	FARAIMETER	SN74LV164A-Q1 MIN TYP MAX 3.09 2.31 0.99	UNIT		
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		3.09		V
V _{IH(D)}	High-level dynamic input voltage	2.31			V
V _{IL(D)}	Low-level dynamic input voltage			0.99	V

(1) Characteristics are for surface-mount packages only.

6.13 Operating Characteristics

T_A = 25°C

	PARAMETER	TEST C	ONDITIONS	V _{cc}	TYP	UNIT
C	Power dissipation capacitance	C ₁ = 50 pF,	f = 10 MHz	3.3 V	48.1	nF
Cpd	Power dissipation capacitance	С <u></u> – 50 рг,		5 V	47.5	μг

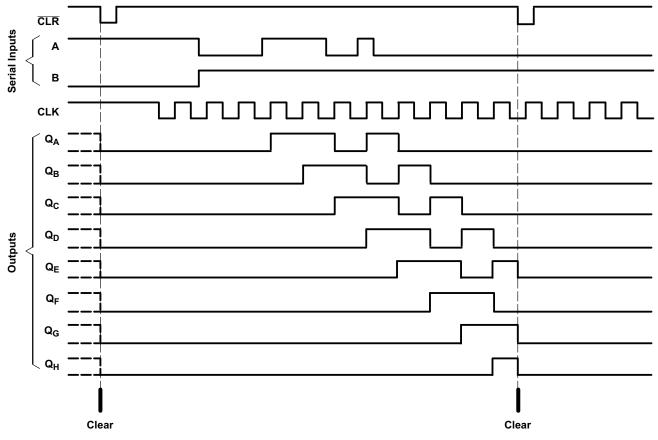
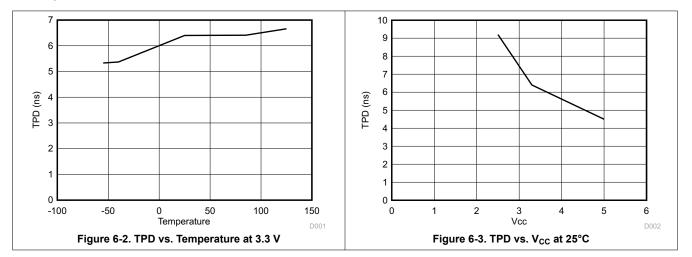


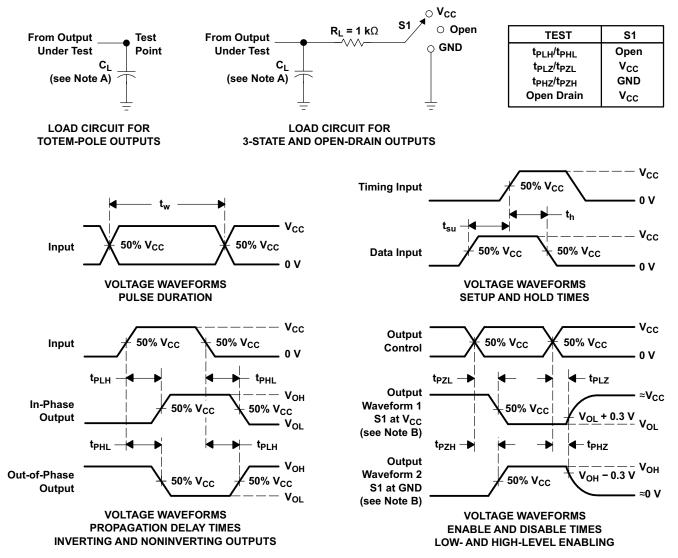
Figure 6-1. Typical Clear, Shift, and Clear Sequences



6.14 Typical Characteristics



7 Parameter Measurement Information



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r \leq 3 ns, t_f \leq 3 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. t_{PL7} and t_{PH7} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PHL} and t_{PLH} are the same as t_{pd} .
- H. All parameters and waveforms are not applicable to all devices.

Figure 7-1. Load Circuit and Voltage Waveforms



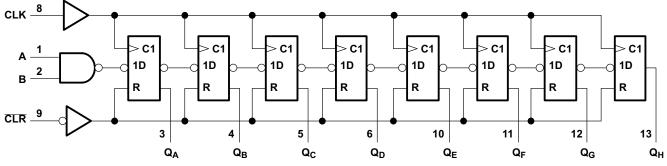
8 Detailed Description

8.1 Overview

The SN74LV164A-Q1 devices are 8-bit parallel-out serial shift registers designed for 2-V to 5.5-V V_{CC} operation.

These devices feature NAND-gated serial (A and B) inputs and an asynchronous clear (CLR) input. The gated serial inputs permit complete control over incoming data, as a low at either input inhibits entry of the new data and resets the first flip-flop to the low level at the next clock pulse. A high-level input enables the other input, which then determines the state of the first flip-flop. Data at the serial inputs can be changed while the clock is high or low, provided the minimum setup time requirements are met. Clocking occurs on the low-to-high-level transition of the clock (CLK) input.

8.2 Functional Block Diagram



Pin numbers shown are for the D, DB, DGV, J, NS, PW, RGY, and W packages.

8.3 Feature Description

The wide operating range allows the device to be used in a variety of systems that use different logic levels. The low propagation delay allows fast switching and higher speeds of operation. In addition, the low ground bounce stabilizes the performance of non-switching outputs while another output is switching.

8.4 Device Functional Modes

	INP	UTS			OUTP	UTS	
CLR	CLK	Α	В	Q _A	Q _B		Q _H
L	Х	Х	Х	L	L		L
Н	L	Х	х	Q _{A0}	Q_{B0}		Q _{H0}
Н	↑	Н	н	Н	Q _{An}		Q_{Gn}
н	↑	L	х	L	Q _{An}		Q_{Gn}
Н	î	Х	L	L	Q _{An}		Q _{Gn}

Table 8-1. Function Table⁽¹⁾⁽²⁾

 Q_{A0}, Q_{B0}, Q_{H0} = the level of Q_A, Q_B, or Q_H, respectively, before the indicated steady-state input conditions were established.

(2) Q_{An}, Q_{Gn} = the level of Q_A or Q_G before the most recent ↑ transition of the clock: indicates a 1-bit shift.



9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The SN74LV164A-Q1 is a low drive CMOS device that can be used for a multitude of bus interface type applications where output ringing is a concern. The low-drive and slow-edge rates will minimize overshoot and undershoot on the outputs.

9.2 Typical Application

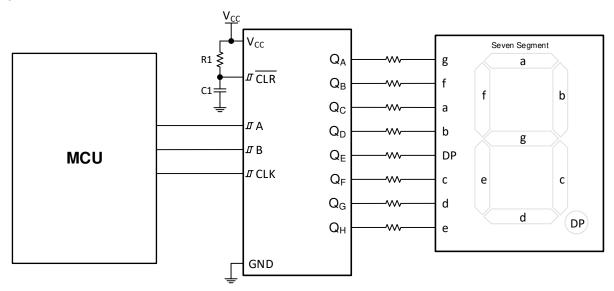


Figure 9-1. Typical Application Schematic

9.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Take care to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads so consider routing and load conditions to prevent ringing.

9.2.2 Detailed Design Procedure

- Recommended input conditions:
 - Rise time and fall time specs. See ($\Delta t/\Delta V$) in *Recommended Operating Conditions*.
 - Specified high and low level. See (V_{IH} and V_{IL}) in *Recommended Operating Conditions*.
 - Inputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid V_{CC} .
- Recommended output conditions:
 - Load currents should not exceed 25 mA per output and 50 mA total for the part.
 - Outputs should not be pulled above V_{CC}.

9.2.3 Application Curves

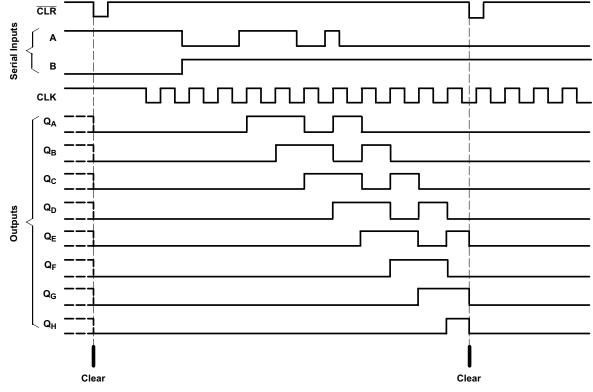


Figure 9-2. Application Timing Diagram

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, TI recommends a 0.1- μ F capacitor and if there are multiple V_{CC} terminals then TI recommends a 0.01- μ F or 0.022- μ F capacitor for each power terminal. Multiple bypass capacitors can be paralleled to reject different frequencies of noise. Frequencies of 0.1 μ F and 1 μ F are commonly used in parallel. The bypass capacitor should be installed as close as possible to the power terminal for best results.



11 Layout 11.1 Layout Guidelines

When using multiple bit logic devices inputs should not ever float.

In many cases, functions or parts of functions of digital logic devices are unused, for example, when only two inputs of a triple-input AND gate are used or only three of the four buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Specified below are the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC} whichever make more sense or is more convenient. Floating outputs is generally acceptable, unless the part is a transceiver. If the transceiver has an output enable pin it will disable the outputs section of the part when asserted. This will not disable the input section of the I.O's so they also cannot float when disabled.

11.2 Layout Example



Figure 11-1. Layout Example



12 Device and Documentation Support

12.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

12.3 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

12.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.5 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
SN74LV164AQWBQARQ1	Active	Production	WQFN (BQA) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVA164
SN74LV164AQWBQARQ1.A	Active	Production	WQFN (BQA) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVA164

⁽¹⁾ **Status:** For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF SN74LV164A-Q1 :

• Catalog : SN74LV164A



NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product



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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LV164AQWBQARQ1	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1



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PACKAGE MATERIALS INFORMATION

19-Dec-2022



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LV164AQWBQARQ1	WQFN	BQA	14	3000	210.0	185.0	35.0

BQA 14

2.5 x 3, 0.5 mm pitch

GENERIC PACKAGE VIEW

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





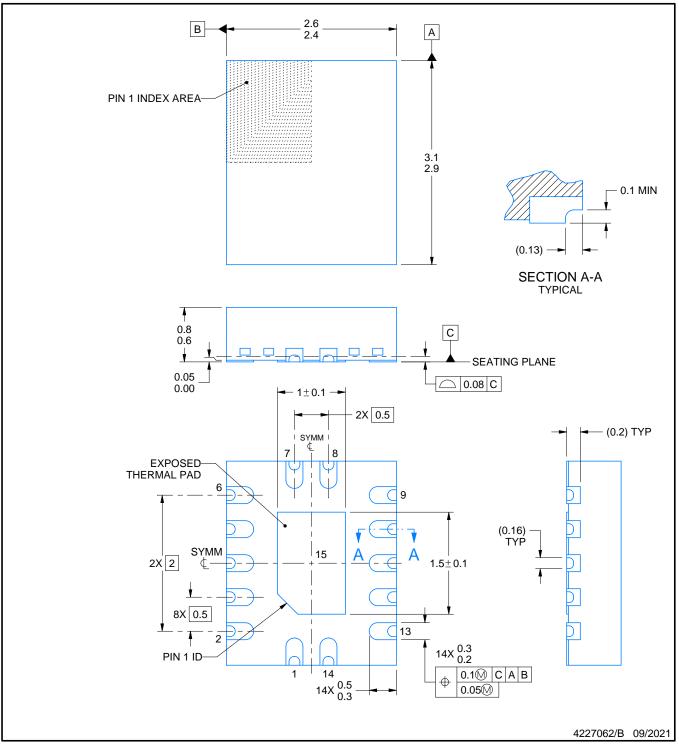
BQA0014B



PACKAGE OUTLINE

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

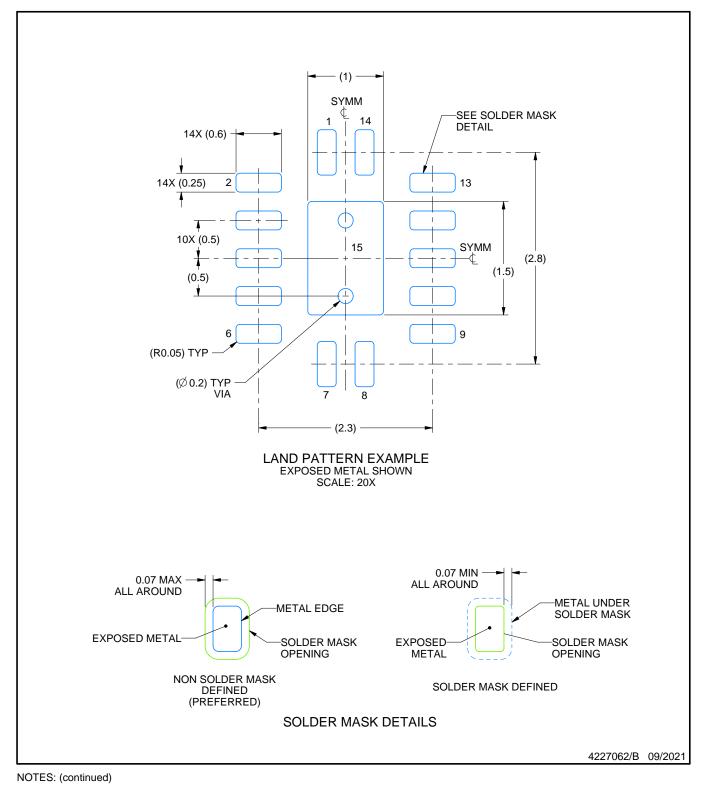


BQA0014B

EXAMPLE BOARD LAYOUT

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



 This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

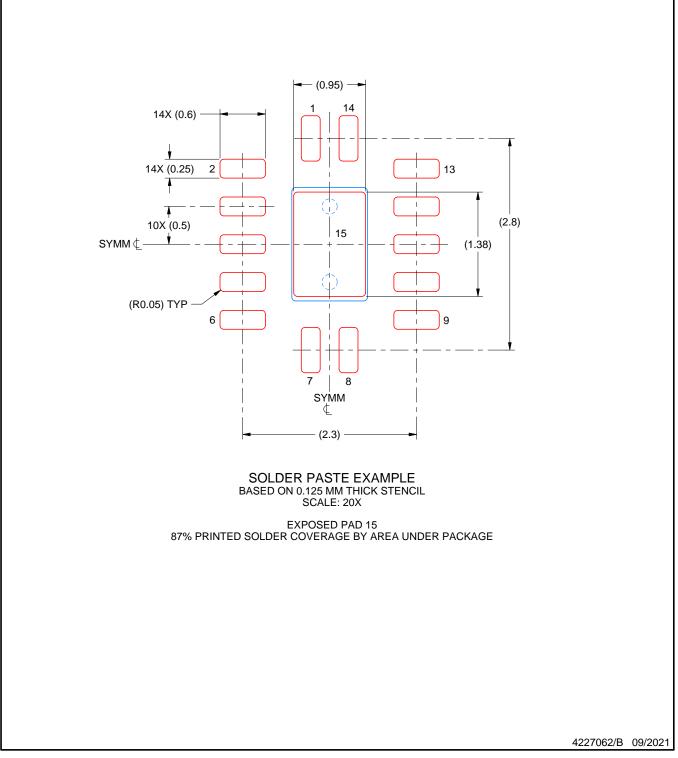


BQA0014B

EXAMPLE STENCIL DESIGN

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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